


<b>Search Notes</b> 	<b>Application/Control No.</b> 10813974	<b>Applicant(s)/Patent Under Reexamination</b> HUEY, CHRISTOPHER A.
	<b>Examiner</b> Nguyen, Khai N	<b>Art Unit</b> 2614

SEARCHED			
Class	Subclass	Date	Examiner
379	211.02	7/05/2007	KNN
455	414	7/05/2007	KNN
379; 455	Updated the above searches	12/1/2008	KNN

SEARCH NOTES			
Search Notes		Date	Examiner
East - USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB		7/05/2007	KNN
Internet - NPL Search		7/05/2007	KNN
Updated East and NPL searches		12/1/2008	KNN

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

--	--